



HEXFET® Power MOSFET

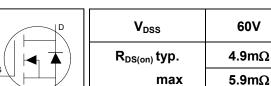
95A

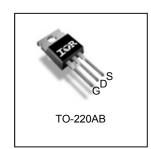
Application

- Brushed motor drive applications
- BLDC motor drive applications
- · Battery powered circuits
- Half-bridge and full-bridge topologies
- Synchronous rectifier applications
- Resonant mode power supplies
- OR-ing and redundant power switches
- DC/DC and AC/DC converters
- DC/AC inverters

Benefits

- Improved gate, avalanche and dynamic dV/dt ruggedness
- Fully characterized capacitance and avalanche SOA
- Enhanced body diode dV/dt and dI/dt capability
- · Lead-free, RoHS compliant





 I_D

G	D	S
Gate	Drain	Source

Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRFB7545PbF	TO-220	Tube	50	IRFB7545PbF

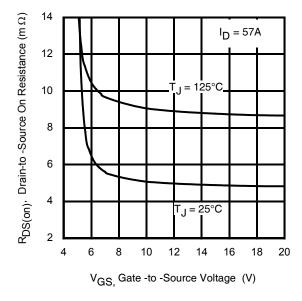


Fig 1. Typical On-Resistance vs. Gate Voltage

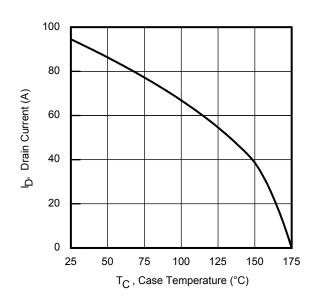


Fig 2. Maximum Drain Current vs. Case Temperature



Absolute Maximum Rating

Symbol	Parameter	Max.	Units
I_D @ T_C = 25°C	Continuous Drain Current, V _{GS} @ 10V	95	
I_D @ T_C = 100°C	Continuous Drain Current, V _{GS} @ 10V	67	Α
I _{DM}	Pulsed Drain Current ①	380	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	125	W
	Linear Derating Factor	0.83	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to + 175	°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting Torque, 6-32 or M3 Screw	10 lbf·in (1.1 N·m)	

Avalanche Characteristics

Symbol	Parameter	Max.	Units
E _{AS} (Thermally limited)	Single Pulse Avalanche Energy ②	140	mJ
E _{AS} (Thermally limited)	Single Pulse Avalanche Energy ®	235	
I_{AR}	Avalanche Current ①	Coo Fig 15, 16, 220, 22h	Α
E _{AR}	Repetitive Avalanche Energy ①	See Fig 15, 16, 23a, 23b	mJ

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ hetaJC}$	Junction-to-Case ⑦		1.21	
$R_{ heta CS}$	Case-to-Sink, Flat Greased Surface	0.50		°C/W
$R_{ hetaJA}$	Junction-to-Ambient		62	

Static @ $T_J = 25$ °C (unless otherwise specified)

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Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	60			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		46		mV/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		4.9	5.9	mΩ	$V_{GS} = 10V, I_D = 57A$
			6.3			$V_{GS} = 6.0V, I_D = 29A$
$V_{GS(th)}$	Gate Threshold Voltage	2.1		3.7	V	$V_{DS} = V_{GS}, I_{D} = 100 \mu A$
ı	Drain-to-Source Leakage Current			1.0		$V_{DS} = 60V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source Leakage Current			150	μA	$V_{DS} = 60V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
ı	Gate-to-Source Forward Leakage			100	nΛ	$V_{GS} = 20V$
I _{GSS}	Gate-to-Source Reverse Leakage			-100	nA	$V_{GS} = -20V$
R_G	Gate Resistance		2.3		Ω	

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- \odot Limited by T_{Jmax}, starting T_J = 25°C, L = 88 μ H, R_G = 50 Ω , I_{AS} = 57A, V_{GS} =10V.
- 4 Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.
- $^{\circ}$ C_{oss} eff. (TR) is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- ⑥ Coss eff. (ER) is a fixed capacitance that gives the same energy as Coss while VDS is rising from 0 to 80% VDSS.
- $\ \ \, \bigcirc \ \, R_{\theta}$ is measured at T_J approximately 90°C.
- & Limited by T_{Jmax} , starting T_J = 25°C, L = 1mH, R_G = 50 Ω , I_{AS} = 22A, V_{GS} =10V.



Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	90			S	$V_{DS} = 25V, I_{D} = 57A$
Q_g	Total Gate Charge		75	110		I _D = 57A
Q_{gs}	Gate-to-Source Charge		19		nC	V _{DS} = 30V
Q_{gd}	Gate-to-Drain Charge		24		IIC	V _{GS} = 10V
Q _{sync}	Total Gate Charge Sync. (Qg – Qgd)		32		Ī	
t _{d(on)}	Turn-On Delay Time		12			V _{DD} = 30V
t _r	Rise Time		72			I _D = 57A
$t_{d(off)}$	Turn-Off Delay Time		44		ns	$R_G = 2.7\Omega$
t _f	Fall Time		43			V _{GS} = 10V ④
C _{iss}	Input Capacitance		4010			V _{GS} = 0V
C _{oss}	Output Capacitance		370			V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance		230		pF	f = 1.0MHz, See Fig.7
Coss eff.(ER)	Effective Output Capacitance (Energy Related)		370		1 '	V _{GS} = 0V, VDS = 0V to 48V®
C _{oss eff.(TR)}	Output Capacitance (Time Related)		470			V _{GS} = 0V, VDS = 0V to 48VS

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			95		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			380		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.2	٧	$T_J = 25^{\circ}C, I_S = 57A, V_{GS} = 0V $ ④
dv/dt	Peak Diode Recovery dv/dt		12		V/ns	$T_J = 175^{\circ}C, I_S = 57A, V_{DS} = 60V$
t _{rr}	Reverse Recovery Time		33		ns	$T_{J} = 25^{\circ}C$ $V_{DD} = 51V$
L _{rr}	Reverse Recovery Time		37		115	$T_J = 125^{\circ}C$ $I_F = 57A$,
	Deverse December Charge		36		20	$T_J = 25^{\circ}C$ di/dt = 100A/µs @
Q_{rr}	Reverse Recovery Charge		48		nC	<u>T_J = 125°C</u>
I _{RRM}	Reverse Recovery Current		2.0		Α	T _J = 25°C



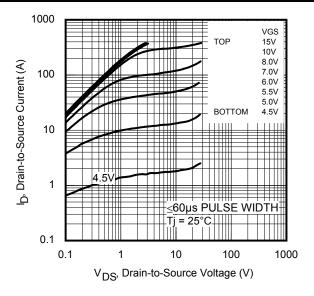


Fig 3. Typical Output Characteristics

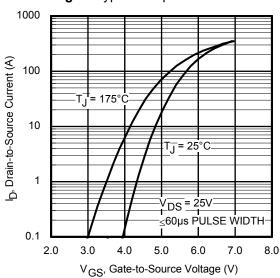


Fig 5. Typical Transfer Characteristics

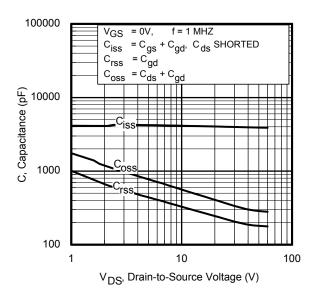


Fig 7. Typical Capacitance vs. Drain-to-Source Voltage

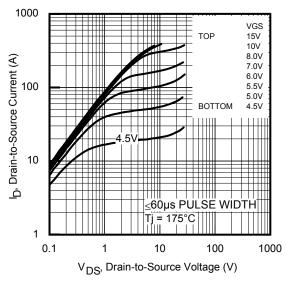


Fig 4. Typical Output Characteristics

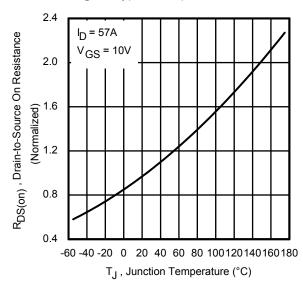


Fig 6. Normalized On-Resistance vs. Temperature

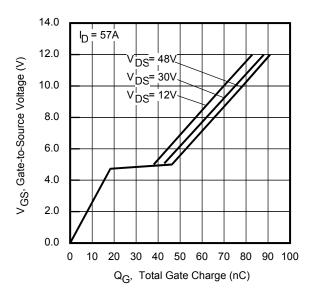


Fig 8. Typical Gate Charge vs. Gate-to-Source Voltage



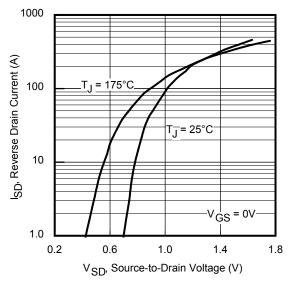


Fig 9. Typical Source-Drain Diode Forward Voltage

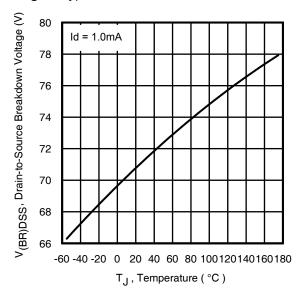


Fig 11. Drain-to-Source Breakdown Voltage

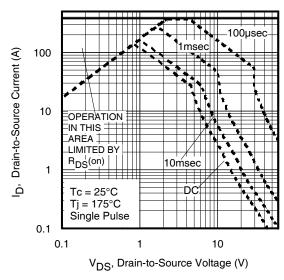


Fig 10. Maximum Safe Operating Area

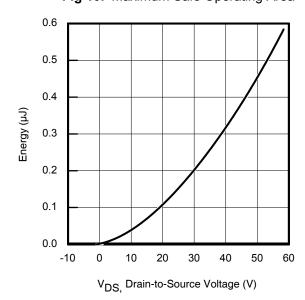


Fig 12. Typical Coss Stored Energy

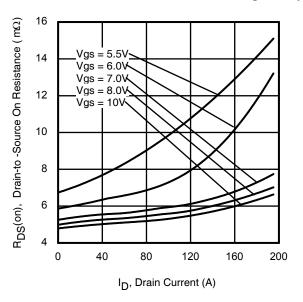


Fig 13. Typical On-Resistance vs. Drain Current

www.irf.com



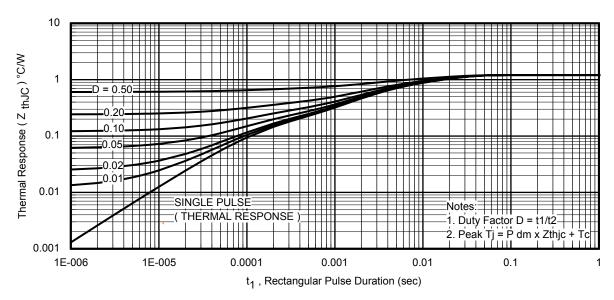


Fig 14. Maximum Effective Transient Thermal Impedance, Junction-to-Case

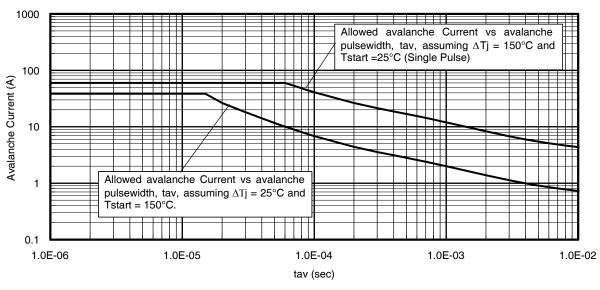


Fig 15. Avalanche Current vs. Pulse Width

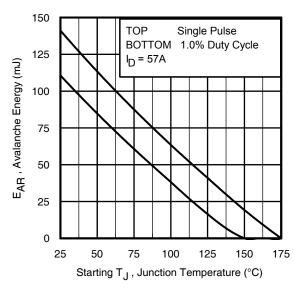


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

1. Avalanche failures assumption:

Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every

- 2. Safe operation in Avalanche is allowed as long $asT_{j\text{max}}$ is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 23a, 23b.
- 4. P_{D (ave)} = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).

 t_{av} = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

 $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see Figures 13) PD (ave) = 1/2 ($1.3 \cdot BV \cdot I_{av}$) = $\Delta T / Z_{thJC}$

 $I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$

 $E_{AS (AR)} = P_{D (ave)} t_{av}$



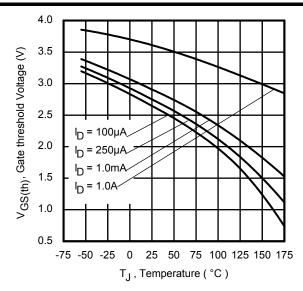


Fig 17. Threshold Voltage vs. Temperature

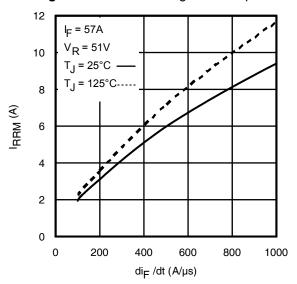


Fig 19. Typical Recovery Current vs. dif/dt

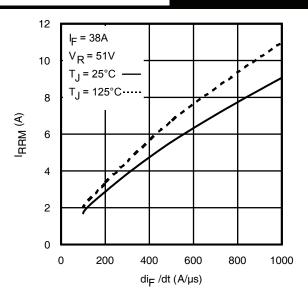


Fig 18. Typical Recovery Current vs. dif/dt

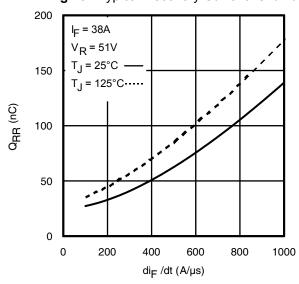


Fig 20. Typical Stored Charge vs. dif/dt

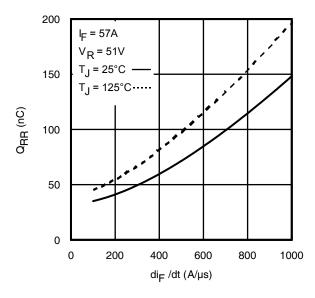


Fig 21. Typical Stored Charge vs. dif/dt



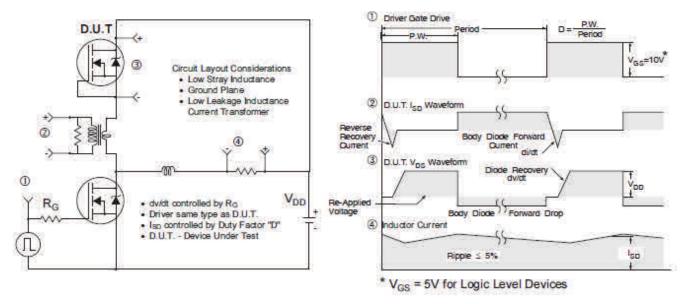


Fig 22. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

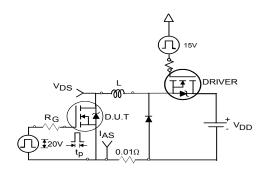


Fig 23a. Unclamped Inductive Test Circuit

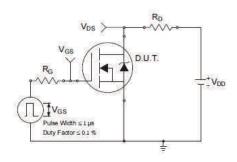


Fig 24a. Switching Time Test Circuit

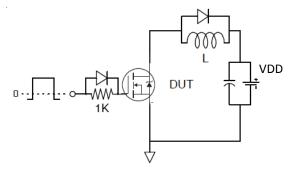


Fig 25a. Gate Charge Test Circuit

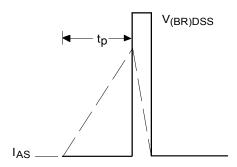


Fig 23b. Unclamped Inductive Waveforms

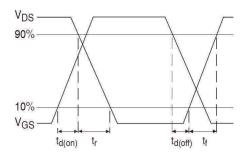


Fig 24b. Switching Time Waveforms

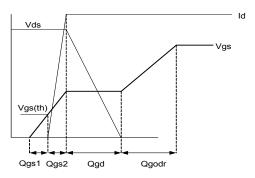
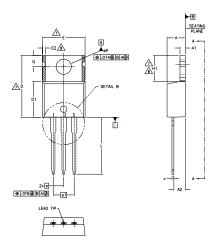
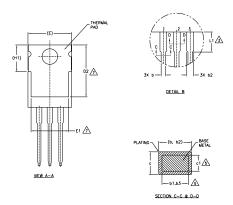


Fig 25b. Gate Charge Waveform



TO-220AB Package Outline (Dimensions are shown in millimeters (inches))





NOTES:

- 1.— DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M— 1994. 2.— DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
- LEAD DIMENSION AND FINISH UNCONTROLLED IN LI
- DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.
- CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIM	ETERS	INC	INCHES		
	MIN.	MAX.	MIN.	MAX.	NOTES	
Α	3.56	4.83	.140	.190		
A1	1.14	1.40	.045	.055		
A2	2.03	2.92	.080	.115		
b	0.38	1.01	.015	.040		
b1	0.38	0.97	.015	.038	5	
b2	1.14	1.78	.045	.070		
b3	1.14	1.73	.045	.068	5	
С	0.36	0.61	.014	.024		
c1	0.36	0.56	.014	.022	5	
D	14.22	16.51	.560	.650	4	
D1	8.38	9.02	.330	.355		
D2	11.68	12.88	.460	.507	7	
E	9.65	10.67	.380	.420	4,7	
E1	6.86	8.89	.270	.350	7	
E2	-	0.76	-	.030	8	
е	2.54	BSC	.100			
e1	5.08	BSC	.200	BSC		
H1	5.84	6.86	.230	.270	7,8	
L	12.70	14.73	.500	.580		
L1	3.56	4.06	.140	.160	3	
ØΡ	3.54	4.08	.139	.161		
Q	2.54	3.42	.100	.135		

LEAD ASSIGNMENTS

HEXEET

IGBTs. CoPACK

1.- GATE 2.- COLLECTOR 3.- EMITTER

DIODES

1.- ANODE 2.- CATHODE 3.- ANODE

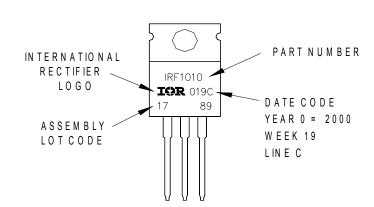
TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010

LOTCODE 1789

ASSEMBLED ON WW 19,2000 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead - Free"



TO-220AB packages are not recommended for Surface Mount Application.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information[†]

Qualification Level	Industrial (per JEDEC JESD47F) ††			
Moisture Sensitivity Level	TO-220 N/A			
RoHS Compliant	Yes			

- † Qualification standards can be found at International Rectifier's web site: http://www.irf.com/product-info/reliability/
- †† Applicable version of JEDEC standard at the time of product release.

Revision History

Date	Comment
11/5/2014	 Updated E_{AS (L =1mH)} = 235mJ on page 2 Updated note 8 "Limited by T_{Jmax}, starting T_J = 25°C, L = 1mH, R_G = 50Ω, I_{AS} = 22A, V_{GS} =10V". on page 2 Updated package outline on page 9



IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA

To contact International Rectifier, please visit http://www.irf.com/whoto-call/

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